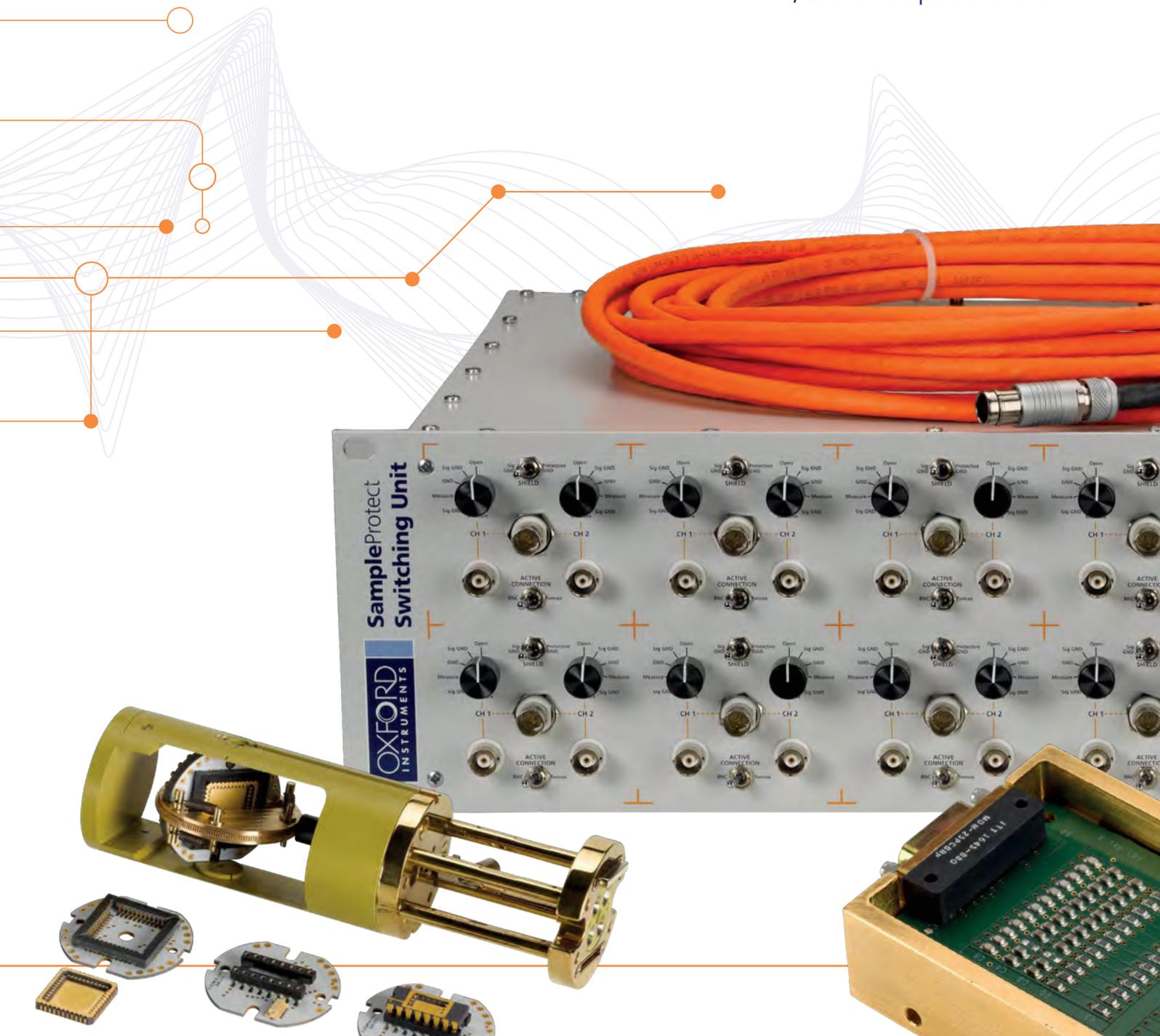


SampleProtect

Switching Unit, universal sample holders and measurement grade cables to maintain ESD protection; rotation; AC, DC and optical access



Why choose **SampleProtect**?

The **SampleProtect** Measurement System is designed to protect the nano-structure devices from being damaged by electrostatic discharge (ESD). From the moment the sample is mounted in our unique sample holder, it is protected from the risk of accidental ESD. This ensures that the sample is protected while moving from the preparation lab to the measurement lab, whether it is just down the corridor or in another country.

Every time a sample is loaded into a cryostat, you can be confident that it is electrically protected – no more waiting until the sample is cold to discover it has been damaged during the loading process.

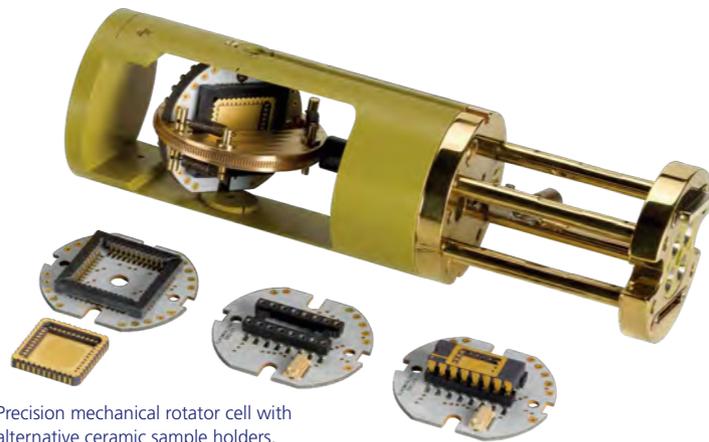
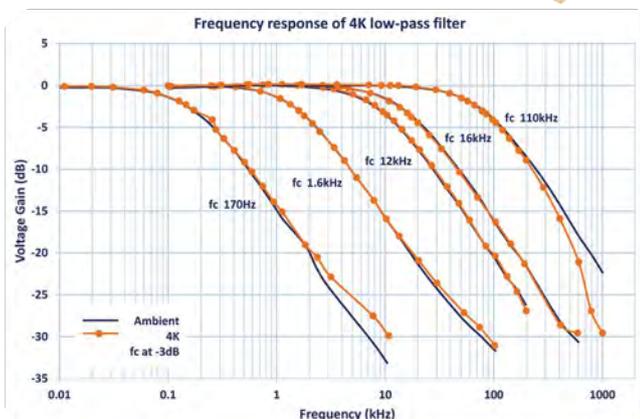
The **SampleProtect** Measurement System comes with a specially designed ESD breakout box, the **SampleProtect** Switching Unit (SPSU), companion sample holders with an equipotential plug and bespoke measurement cables to ensure signal quality.

Easy to use

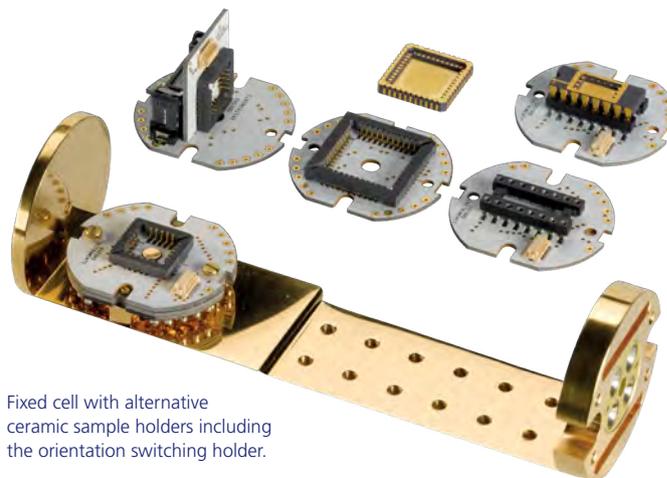
The **SampleProtect** Measurement System can be used over a wide variety of temperatures with the entire Oxford Instruments' product range and new experimental measurement probes.

- High quality measurement grade cables for low level signals
- Low noise twisted pairs with channel dependent configurable shielding for low cross-talk
- Switchable BNC or Twinax connection options
- 24 connections in 12 twisted pairs
- Reliable build and trusted design

Cold (4 K) low-pass
24-line filter in
screened enclosure.



Precision mechanical rotator cell with alternative ceramic sample holders.



Fixed cell with alternative ceramic sample holders including the orientation switching holder.

Total measurement solution

SampleProtect Measurement System can be used for various applications including materials, device, optical and opto-electrical characterisation; and electrical measurements.

All sample holders are transferable between probes and inserts, e.g. between a sample-in-vacuum (SIV) rotator probe and fixed sample-in-gas (SIG) probe, or even a **HelioxVT** or **KelvinoxJT** procured from us.

This will significantly reduce your measurement time by minimising the risk of ground loops and stop accidental ESD damage affecting your devices.



Probe chassis universal interface with piezo electric cell and orientation switching holder.

Visit www.oxinst.com/sampleprotect or email nanoscience@oxinst.com

Main service locations: UK, USA, Germany, China, Japan and India

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